



HORIBA Scientific offers many types of training courses tailored to your particular requirements:

- **A la carte** training courses at our approved HORIBA Scientific training center. Learn and share your experience with other users and acquire the basics of the technique. You will be able to directly use this knowledge for your applications in your own laboratory.
- **Training on-site**, performed by one of our HORIBA Scientific application experts.

Our trainers are experts in each technique. They will provide trainings advice and guidance to make the most of your HORIBA Scientific instrument.

You will gain confidence and experience in the analysis of your samples.

To get the entire program and to get registered,  
please contact us at

[training.hfr@horiba.com](mailto:training.hfr@horiba.com)

Certificates are given to every attendee for every course.

All trainings are held in France or at your location and are conducted in English.



## Raman

### Acquire theoretical and practical knowledge on Raman spectrometers

**Reference:** RAM1 - **RAMAN for Beginners**  
**Duration:** 3 days, from 9 am to 5:30 pm  
**Dates:** February 12-14, 2018  
May 14-16, 2018  
July 9-11, 2018  
October 8-10, 2018  
November 19-21, 2018

### Optional Add-ons days for RAM1 training

#### Learn how to use the DuoScan option

**Reference:** RAM1DS - **RAMAN DUOSCAN**  
**Duration:** 1 day, from 9 am to 5:30 pm  
**Dates:** February 15 & 16, 2018  
May 17 & 18, 2018  
October 11 & 12, 2018

#### Understand the Particle Finder Module

**Reference:** RAM1PF - **PARTICLE FINDER**  
**Duration:** 1 day, from 9 am to 5:30 pm  
**Dates:** February 15 & 16, 2018  
May 17 & 18, 2018  
October 11 & 12, 2018

#### Understand TERS Technology

**Reference:** RAM1TERS - **TERS**  
**Duration:** 1 day, from 9 am to 5:30 pm  
**Dates:** February 15 & 16, 2018  
May 17 & 18, 2018  
October 11 & 12, 2018

#### Acquire theoretical and practical knowledge on ULF kit

**Reference:** RAM1ULF - **Ultra Low Frequency kit**  
**Duration:** 1 day, from 9 am to 5:30 pm  
**Dates:** February 15 & 16, 2018  
May 17 & 18, 2018  
October 11 & 12, 2018

## Acquire theoretical and practical knowledge on SERS

**Reference:** RAM2 - **Raman SERS**

**Duration:** 1 day, from 9 am to 5:30 pm

**Dates:** February 15, 2018  
July 12, 2018  
November 22, 2018

## Understand the Multivariate Analysis Module

**Reference:** RAM3 - **Raman Multivariate Analysis**

**Duration:** 1 day, from 9 am to 5:30 pm

**Dates:** February 16, 2018  
July 13, 2018  
November 23, 2018

## Understand Raman Spectroscopy & SPM Techniques

**Reference:** RAM4 - **Raman & SPM**

**Duration:** 3 days, from 9 am to 5:30 pm

**Dates:** February 12-14, 2018  
May 14-16, 2018  
November 19-21, 2018

## Fluorescence

### Acquire theoretical and practical knowledge on fluorescence

**Reference:** FLUO1 - **Fluorescence for Beginners**

**Duration:** 3 days, from 9 am to 5:30 pm

**Dates:** March 19-21, 2018  
May 28-30, 2018  
October 15-17, 2018

### Learn how to use the software

**Reference:** FLUO2 - **Software**

**Duration:** 1 day, from 9 am to 5:30 pm

**Dates:** March 22, 2018  
May 31, 2018  
October 18, 2018

## Acquire theoretical and practical knowledge on lifetime fluorescence

**Reference:** FLUO3 - **Lifetime**  
**Duration:** 1 day, from 9 am to 5:30 pm  
**Dates:** March 23, 2018  
June 1, 2018  
October 19, 2018

## Acquire theoretical and practical knowledge on Aqualog fluorescence (EEMs)

**Reference:** FLUO4 - **Aqualog**  
**Duration:** 1 day, from 9 am to 5:30 pm  
**Dates:** April 3, 2018  
June 4, 2018  
October 22, 2018

## Ellipsometry

### Learn theory and modeling techniques

**Reference:** ELL1 - **Ellipsometry for Beginners**  
**Duration:** 3 days, from Monday 9 am to 5:30 pm  
**Dates:** March 26-28, 2018  
November 19-21, 2018

### Learn modeling techniques on complex sample

**Reference:** ELL2 - **Advanced Ellipsometry Techniques**  
**Duration:** 3 days, from 9 am to 5:30 pm  
**Dates:** June 5-7, 2018  
December 3-5, 2018





## SPRi

### Learn how to use the OpenPlex

**Reference:** SPRi1 - **OpenPlex**  
**Duration:** 3 days, from 9 am to 5:30 pm  
**Dates:** February 12-14, 2018  
July 2-4, 2018

### Learn how to get the best from the XelPlex

**Reference:** SPRi2 - **XelPlex**  
**Duration:** 4 days, from 9 am to 5:30 pm  
**Dates:** May 14-17, 2018  
October 22-25, 2018

### Learn how to run your samples

**Reference:** SPRi3 - **Customer training on their application**  
**Duration:** 4 days,  
from 9 am to 5:30 pm  
**Dates:** March 12-15, 2018  
September 10-13, 2018



## GDOES

### Learn theory and practice Glow Discharge Spectrometry

**Reference:** GD1- **GD for beginners**  
**Duration:** 2 days, from 9 am to 5:30 pm  
**Dates:** February 20-21, 2018  
October 8-9, 2018

### Learn how to quantify with GDL

**Reference:** GD2 - **GD quantification**  
**Duration:** 2 days, from 9 am to 5:30 pm  
**Dates:** February 19-20, 2018  
October 10-11, 2018



## Learn how to measure depth with DiP

**Reference:** GD3 - DiP  
**Duration:** 1 day, from 9 am to 5:30 pm  
**Dates:** February 23, 2018  
October 12, 2018

## ICP-OES

### Learn how to use and optimize your ICP-OES

**Reference:** ICP - ICP-OES  
**Duration:** 5 days, from 9 am to 5:30 pm  
**Dates:** March 5-9, 2018  
July 2-6, 2018  
October 15-19, 2018

## PSA

### How to optimize any sample analysis

**Reference:** PSA1- Laser Diffraction  
**Duration:** 1 day, from 9 am to 5:30 pm  
**Dates:** March 13, 2018  
October 8, 2018

### Learn how to interpret results in DLS

**Reference:** PSA2 - Light Scattering Technique  
**Duration:** 1 day, from 9 am to 5:30 pm  
**Dates:** March 14, 2018  
October 9, 2018

## C/S/O/N/H Analyzer

### Learn how to maximise results from the EMIA

**Reference:** HOR1- C/S Analyzer  
**Duration:** 1 day, from 9 am to 5:30 pm  
**Dates:** March 13, 2018  
October 1, 2018



## Learn how to maximise results from the EMGA

**Reference:** HOR2 - O/N/H Analyzer  
**Duration:** 1 day, from 9 am to 5:30 pm  
**Dates:** March 14, 2018  
October 2, 2018

## S & CI Analyzer

### Learn how to optimize S & CI determination in Petroleum Products

**Reference:** HOR3 - S & CI analyzer for Petroleum products  
**Duration:** 1 day, from 9 am to 5:30 pm  
**Dates:** March 15, 2018  
October 3, 2018

## XGT/MESA 50

### Learn how to optimize the XRF Fluorescence analyzer

**Reference:** HOR4 - X-Ray Fluorescence analyzer  
**Duration:** 1 day, from 9 am to 5:30 pm  
**Dates:** March 16, 2018  
October 4, 2018

## On-site Training

### Customized training at your site

**Reference:** TRAINSITE  
**Duration:** 1 day, from 9 am to 5:30 pm  
**Dates:** On request

## On-line Training

### Direct analytical help

**Reference:** TRAINLINE  
**Duration:** 4 hours  
**Dates:** On request

## Location

Depending on the technique, there are three locations in France:

- Longjumeau (20 km from Paris),
- Palaiseau (26 km from Paris),
- Villeneuve d'Ascq (220 km from Paris)

Additional locations:

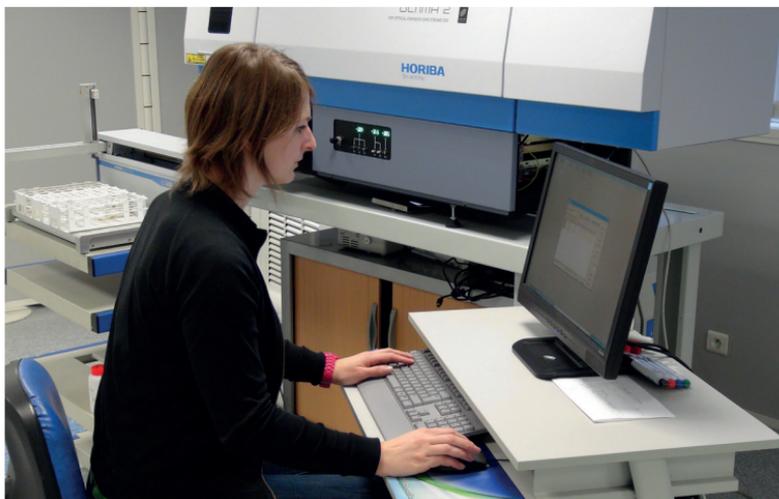
- At your facility for on-site training courses.
- Training courses can also take place in subsidiaries in Germany or in the USA.

## Registration

To register please request the form, or go the web page.

[training.hfr@horiba.com](mailto:training.hfr@horiba.com)

[www.horiba.com/scientific/training](http://www.horiba.com/scientific/training)





# HORIBA

Scientific





## Ultima Expert

### Emission spectrometry

- Unique plasma torch design offers the most versatile and accurate analyses
- Accessories for varied applications
- High resolution and full wavelength coverage
- Easy to handle, easy to maintain



## XploRA Nano

### AFM-Raman system

- Fully automated operation. Start measuring within minutes, not hours!
- Compatible with red and NIR Raman excitation lines thanks to 1.3  $\mu\text{m}$  AFM laser diode
- Top and side AFM-Raman optical coupling with high NA (up to 100X, 0.7NA)
- Co-localized AFM-Raman image with optimized illumination spot size from the top
- TERS-proven label-free chemical nano-imaging
- Ag AFM-TERS tips available





## GD Profiler 2

### Elemental composition profiling

- Conductive, non-conductive and hybrid samples
- Quantitative depth profiling
- All elements can be simultaneously measured, including light elements (C, H, O, N, Cl, Li, Na, etc.)
- Depth resolution at the nm range
- Patented DiP – built-in interferometer for direct measurement of crater depth



## Fluorolog<sup>®</sup> -3

### Fluorescence spectroscopy

- Light source: 450 W Xenon lamp
- Spectral range: 185 nm~14  $\mu$ m
- Sensitivity (SNR):
  - > 15000:1 FSD method
  - > 30000:1 RMS method
- All-reflective optics
- Fully computer-controlled
- Interchange wide range of computer controlled accessories: spectrometers, detectors, sources, and more
- TCSPC Fluorescence lifetime capability





## LA-960

### Particle size analyzer

- Laser Diffraction
- Measurement range: 10 nm-5000  $\mu\text{m}$
- Sample types: Powder, emulsion, suspension
- Sample amount: 10 mg~5 g
- Various dispersion modules: Wet/Dry analysis, low/high quantity
- Measurement time: 1 minute (from liquid filling, sample dispersion, measurement data acquisition, rinse)
- Solvent compliant
- Ultrasonic probe to improve dispersion





## UVISEL PLUS

Reference Spectroscopic Ellipsometer

- New optics and electronics for fast and accurate measurements
- Phase modulation with a high frequency PEM for pure and efficient polarization without moving optical components
- 3 Achromatic microspots down to 50  $\mu\text{m}$
- Spectral range from 190 nm~ 920 nm, or 190 nm~2100 nm



**2018**

# Training Courses



Explore the future

Automotive Test Systems | Process & Environmental | Medical | Semiconductor | Scientific

**HORIBA**